# imall

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560

0.95

4.5

**PG-TO252** 

V

Ω

А

2 (tab)

pin 3

V<sub>DS</sub> @ T<sub>imax</sub>

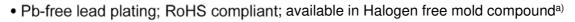
R<sub>DS(on)</sub>

 $I_{\rm D}$ 

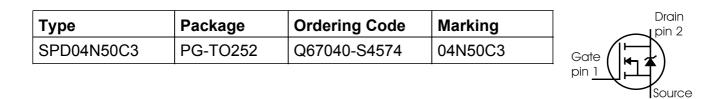
# Cool MOS<sup>™</sup> Power Transistor

#### Feature

- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- Ultra low effective capacitances
- Improved transconductance



• Qualified according to JEDEC<sup>0)</sup> for target applications



#### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Continuous drain current	I <sub>D</sub>		А
<i>T</i> <sub>C</sub> = 25 °C		4.5	
<i>T</i> <sub>C</sub> = 100 °C		2.8	
Pulsed drain current, $t_p$ limited by $T_{jmax}$	I <sub>D puls</sub>	13.5	
Avalanche energy, single pulse	E <sub>AS</sub>	130	mJ
$I_{\rm D}$ = 3.4 A, $V_{\rm DD}$ = 50 V			
Avalanche energy, repetitive $t_{AR}$ limited by $T_{jmax}^{1}$	E <sub>AR</sub>	0.4	
$I_{\rm D}$ = 4.5 A, $V_{\rm DD}$ = 50 V			
Avalanche current, repetitive $t_{AR}$ limited by $T_{jmax}$	I <sub>AR</sub>	4.5	А
Gate source voltage	V <sub>GS</sub>	±20	V
Gate source voltage AC (f >1Hz)	V <sub>GS</sub>	±30	
Power dissipation, $T_{\rm C}$ = 25°C	P <sub>tot</sub>	50	W
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55 +150	°C
Reverse diode dv/dt <sup>5)</sup>	dv/dt	15	V/ns

<sup>a)</sup> non-Halogen free (OPN: SPD04N50C3BT); Halogen free (OPN: SPD04N50C3AT)



#### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Drain Source voltage slope	d <i>v</i> /dt	50	V/ns
$V_{\rm DS}$ = 400 V, $I_{\rm D}$ = 4.5 A, $T_{\rm j}$ = 125 °C			

#### **Thermal Characteristics**

Parameter	Symbol	Values		Unit	
		min.	typ.	max.	
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	2.5	K/W
Thermal resistance, junction - ambient, leaded	R <sub>thJA</sub>	-	-	62	
SMD version, device on PCB:	R <sub>thJA</sub>				
@ min. footprint		-	-	62	
@ 6 cm <sup>2</sup> cooling area $^{2)}$		-	35	-	
Soldering temperature, reflow soldering, MSL3	T <sub>sold</sub>	-	-	260	°C
1.6 mm (0.063 in.) from case for 10s					

# **Electrical Characteristics,** at *T*j=25°C unless otherwise specified

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =0.25mA	500	-	-	V
Drain-Source avalanche	V <sub>(BR)DS</sub>	V <sub>GS</sub> =0V, <i>I</i> <sub>D</sub> =4.5A	-	600	-	
breakdown voltage						
Gate threshold voltage	V <sub>GS(th)</sub>	$I_{\rm D}$ =200 $\mu$ A, $V_{\rm GS}$ = $V_{\rm DS}$	2.1	3	3.9	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DSS}$ $V_{\rm DS}$ =500V, $V_{\rm GS}$ =0V,				μA
		<i>T</i> j=25°C,	-	0.1	1	
		<i>T</i> j=150°C	-	-	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	-	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	<i>V</i> <sub>GS</sub> =10V, <i>I</i> <sub>D</sub> =2.8A,				Ω
		<i>T</i> j=25°C	-	0.85	0.95	
		<i>T</i> j=150°C	-	2.3	-	
Gate input resistance	R <sub>G</sub>	<i>f</i> =1MHz, open Drain	-	1.4	_	



Parameter	Symbol	Conditions		Values	Unit	
			min.	typ.	max.	
Transconductance	<i>g</i> fs	V <sub>DS</sub> ≥2*I <sub>D</sub> *R <sub>DS(on)max</sub> ,	-	4.4	-	S
		/ <sub>D</sub> =2.8A				
Input capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V,	-	470	-	pF
Output capacitance	C <sub>oss</sub>	f=1MHz	-	160	-	1
Reverse transfer capacitance	C <sub>rss</sub>	•	-	15	-	1
Effective output capacitance, 3)	C <sub>o(er)</sub>	V <sub>GS</sub> =0V,	-	27	-	pF
energy related		V <sub>DS</sub> =0V to 400V				
Effective output capacitance, <sup>4)</sup>	C <sub>o(tr)</sub>		-	44	-	
time related						
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =350V, V <sub>GS</sub> =0/10V,	-	10	-	ns
Rise time	<i>t</i> <sub>r</sub>	/ <sub>D</sub> =4.5A, <i>R</i> <sub>G</sub> =18Ω	-	5	-	]
Turn-off delay time	<i>t</i> d(off)		-	70	-	]
Fall time	t <sub>f</sub>		-	10	-	1

# **Electrical Characteristics** , at $T_i = 25$ °C, unless otherwise specified

#### **Gate Charge Characteristics**

1			-	1	
Q <sub>gs</sub>	V <sub>DD</sub> =400V, <i>I</i> <sub>D</sub> =4.5A	-	2.2	-	nC
Q <sub>gd</sub>		-	10	-	
Qg	V <sub>DD</sub> =400V, I <sub>D</sub> =4.5A,	-	22	-	
_	V <sub>GS</sub> =0 to 10V				
V <sub>(plateau)</sub>	V <sub>DD</sub> =400V, I <sub>D</sub> =4.5A	-	5	-	V
	Q <sub>gd</sub> Q <sub>g</sub>	$\begin{array}{c} Q_{\rm gd} \\ Q_{\rm g} \\ Q_{\rm g} \\ V_{\rm DD} = 400 \text{V}, I_{\rm D} = 4.5 \text{A}, \end{array}$	$ \begin{array}{c}     Q_{gd} & - \\     Q_{g} & V_{DD} = 400 \text{V}, I_{D} = 4.5 \text{A}, \\     V_{GS} = 0 \text{ to } 10 \text{V} \end{array} $	$Q_{gd}$ $P_{DD}$ + 60 V, $P_{D}$ + 61 V $P_{DD}$ $Q_{gd}$ -         10 $Q_{g}$ $V_{DD}$ =400V, $I_{D}$ =4.5A, -         22 $V_{GS}$ =0 to 10V         -         10	$Q_{gd}$ $P_{DD}$ + 50 (r, r, p) + 50 (r

<sup>0</sup>J-STD20 and JESD22

<sup>1</sup>Repetitve avalanche causes additional power losses that can be calculated as  $P_{AV} = E_{AR}^* f$ .

<sup>2</sup>Device on 40mm\*40mm\*1.5mm epoxy PCB FR4 with 6cm<sup>2</sup> (one layer, 70 µm thick) copper area for drain connection. PCB is vertical without blown air.

 ${}^{3}C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

 ${}^{4}C_{o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

 ${}^{5}I_{SD}$ <= $I_{D}$ , di/dt<=400A/us, V<sub>DClink</sub>=400V, V<sub>peak</sub><V<sub>BR, DSS</sub>, T<sub>j</sub><T<sub>j,max</sub>. Identical low-side and high-side switch.

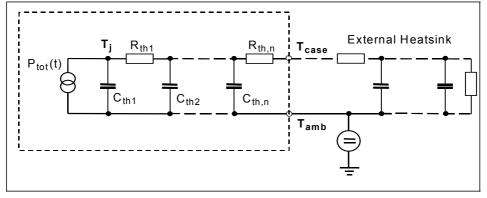


Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Inverse diode continuous	I <sub>S</sub>	<i>T</i> C=25°C	-	-	4.5	Α
forward current						
Inverse diode direct current,	/ <sub>SM</sub>		-	-	13.5	
pulsed						
Inverse diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>F</sub> =I <sub>S</sub>	-	1	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =400V, I <sub>F</sub> =I <sub>S</sub> ,	-	280	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub>/dt</i> =100A/µs	-	2.3	-	μC
Peak reverse recovery current	<i>I</i> <sub>rrm</sub>		-	16	-	A
Peak rate of fall of reverse	di <sub>rr</sub> /dt		-	860	-	A/µs
recovery current						

#### **Electrical Characteristics**, at $T_i$ = 25 °C, unless otherwise specified

#### **Typical Transient Thermal Characteristics**

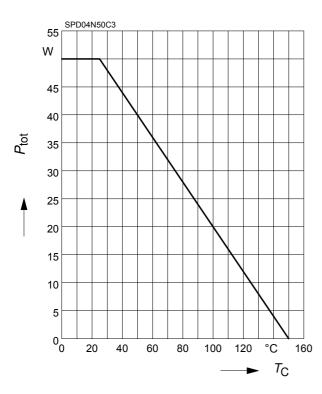
Symbol	Value	Unit	Jnit Symbol	Value	Unit
	typ.			typ.	
Thermal r	esistance		Thermal c	apacitance	
R <sub>th1</sub>	0.039	K/W	C <sub>th1</sub>	0.00007347	Ws/K
R <sub>th2</sub>	0.074		C <sub>th2</sub>	0.0002831	
R <sub>th3</sub>	0.132		C <sub>th3</sub>	0.0004062	
R <sub>th4</sub>	0.555		C <sub>th4</sub>	0.001215	
R <sub>th5</sub>	0.529		C <sub>th5</sub>	0.00276	
R <sub>th6</sub>	0.169		C <sub>th6</sub>	0.029	





#### **1** Power dissipation

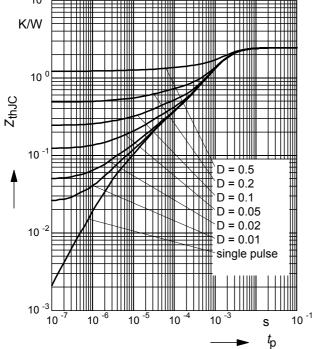
# $P_{\text{tot}} = f(T_{\text{C}})$



#### **3 Transient thermal impedance**

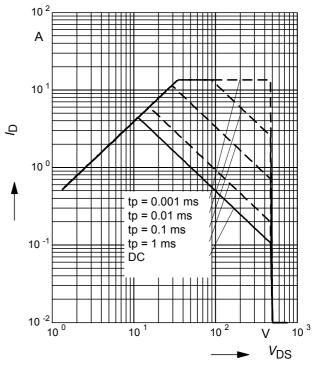
 $Z_{\text{thJC}} = f(t_{\text{p}})$ 

$$10^{1} - \frac{10^{1}}{10^{1}}$$



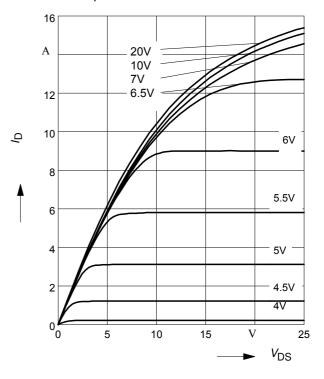
#### 2 Safe operating area

 $I_{\rm D} = f(V_{\rm DS})$ parameter : D = 0 ,  $T_{\rm C}$ =25°C



#### 4 Typ. output characteristic

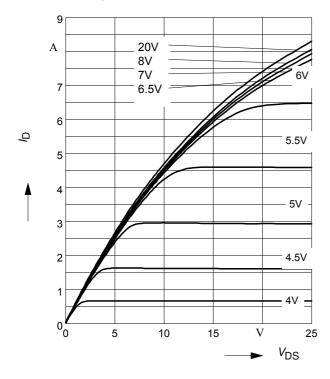
 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j}=25^{\circ}{\rm C}$ parameter:  $t_{\rm p} = 10 \ \mu{\rm s}, V_{\rm GS}$ 





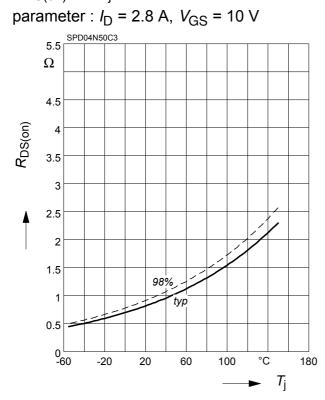
#### 5 Typ. output characteristic

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j}=150^{\circ}{\rm C}$ parameter:  $t_{\rm p} = 10 \ \mu{\rm s}, V_{\rm GS}$ 



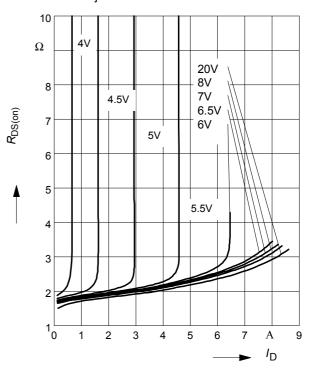
#### 7 Drain-source on-state resistance

 $R_{\text{DS(on)}} = f(T_{j})$ 



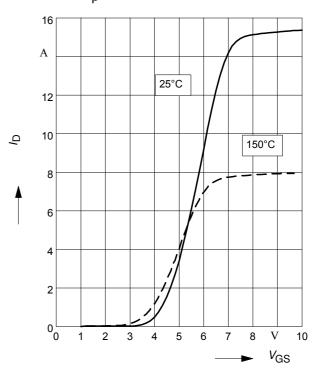
#### 6 Typ. drain-source on resistance

 $R_{\text{DS(on)}} = f(I_{\text{D}})$ parameter:  $T_{\text{i}} = 150^{\circ}\text{C}$ ,  $V_{\text{GS}}$ 



#### 8 Typ. transfer characteristics

 $I_{D}$ = f (  $V_{GS}$  );  $V_{DS}$   $\geq$  2 x  $I_{D}$  x  $R_{DS(on)max}$ parameter:  $t_{p}$  = 10 µs

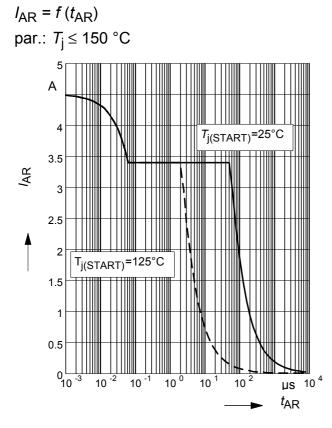




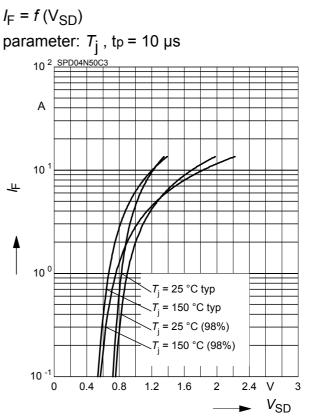
#### 9 Typ. gate charge

 $V_{\rm GS} = f (Q_{\rm Gate})$ parameter:  $I_{\rm D}$  = 4.5 A pulsed SPD04N50C3 V 12 Vgs 0.2 V<sub>DS max</sub> 10 0.8 V<sub>DS max</sub> 8 6 4 2 000 32 4 8 12 16 20 24 nC **Q**Gate

#### 11 Avalanche SOA

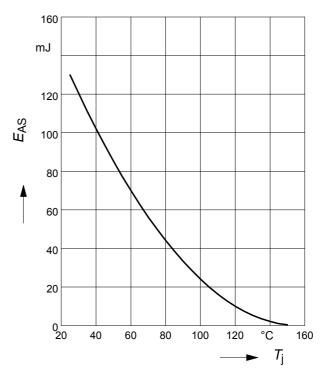


#### 10 Forward characteristics of body diode



#### 12 Avalanche energy

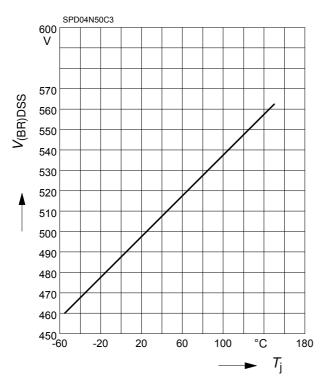
 $E_{AS} = f(T_j)$ par.:  $I_D = 3.4 \text{ A}, V_{DD} = 50 \text{ V}$ 





#### 13 Drain-source breakdown voltage

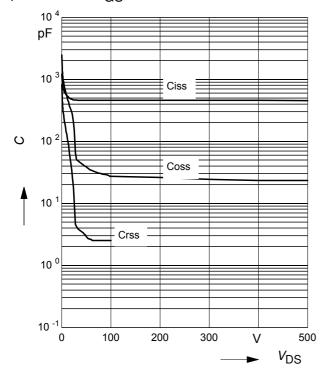
 $V_{(BR)DSS} = f(T_j)$ 



# 15 Typ. capacitances

 $C = f(V_{\rm DS})$ 

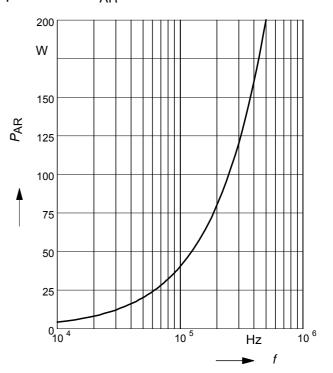
```
parameter: V<sub>GS</sub>=0V, f=1 MHz
```



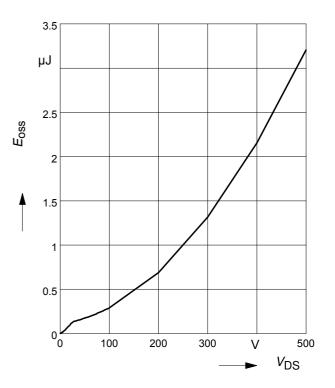
#### 14 Avalanche power losses

 $P_{AR} = f(f)$ 

parameter: EAR=0.4mJ

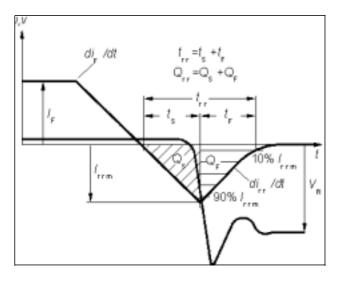


# **16 Typ.** $C_{\text{OSS}}$ stored energy $E_{\text{OSS}} = f(V_{\text{DS}})$



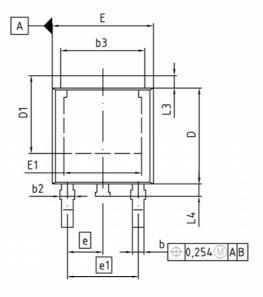


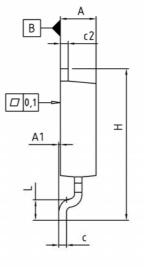
Definition of diodes switching characteristics

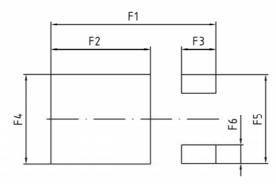




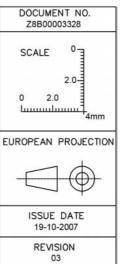
### PG-TO252-3-1, PG-TO252-3-11, PG-TO252-3-21 (D-PAK)







DIM	MILLIMETERS		INCH	IES	
DIM	MIN	MAX	MIN	MAX	1
Α	2.16	2.41	0.085	0.095	1
A1	0.00	0.15	0.000	0.006	1
b	0.64	0.89	0.025	0.035	1
b2	0.65	1.15	0.026	0.045	
b3	5.00	5.50	0.197	0.217	1
с	0.46	0.60	0.018	0.024	
c2	0.46	0.98	0.018	0.039	1
D	5.97	6.22	0.235	0.245	1
D1	5.02	5.84	0.198	0.230	1
E	6.40	6.73	0.252	0.265	1
E1	4.70	5.21	0.185	0.205	1
е	2.	29	0.0	90	1
e1	4.	57	0.180		1
N		3 3		3	EUF
н	9.40	10.48	0.370	0.413	1 1
L	1.18	1.70	0.046	0.067	1
L3	0.90	1.25	0.035	0.049	1   .
L4	0.51	1.00	0.020	0.039	1   1
F1	10.50	10.70	0.413	0.421	1
F2	6.30	6.50	0.248	0.256	1
F3	2.10	2.30	0.083	0.091	1
F4	5.70	5.90	0.224	0.232	1 🛏
F5	5.66	5.86	0.223	0.231	1
F6	1.10	1.30	0.043	0.051	1





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